

Electronic Supplementary Information

Perpendicularly aligned nanodomains on
versatile substrates *via* rapid thermal annealing
assisted by liquid crystalline ordering in block
copolymer films

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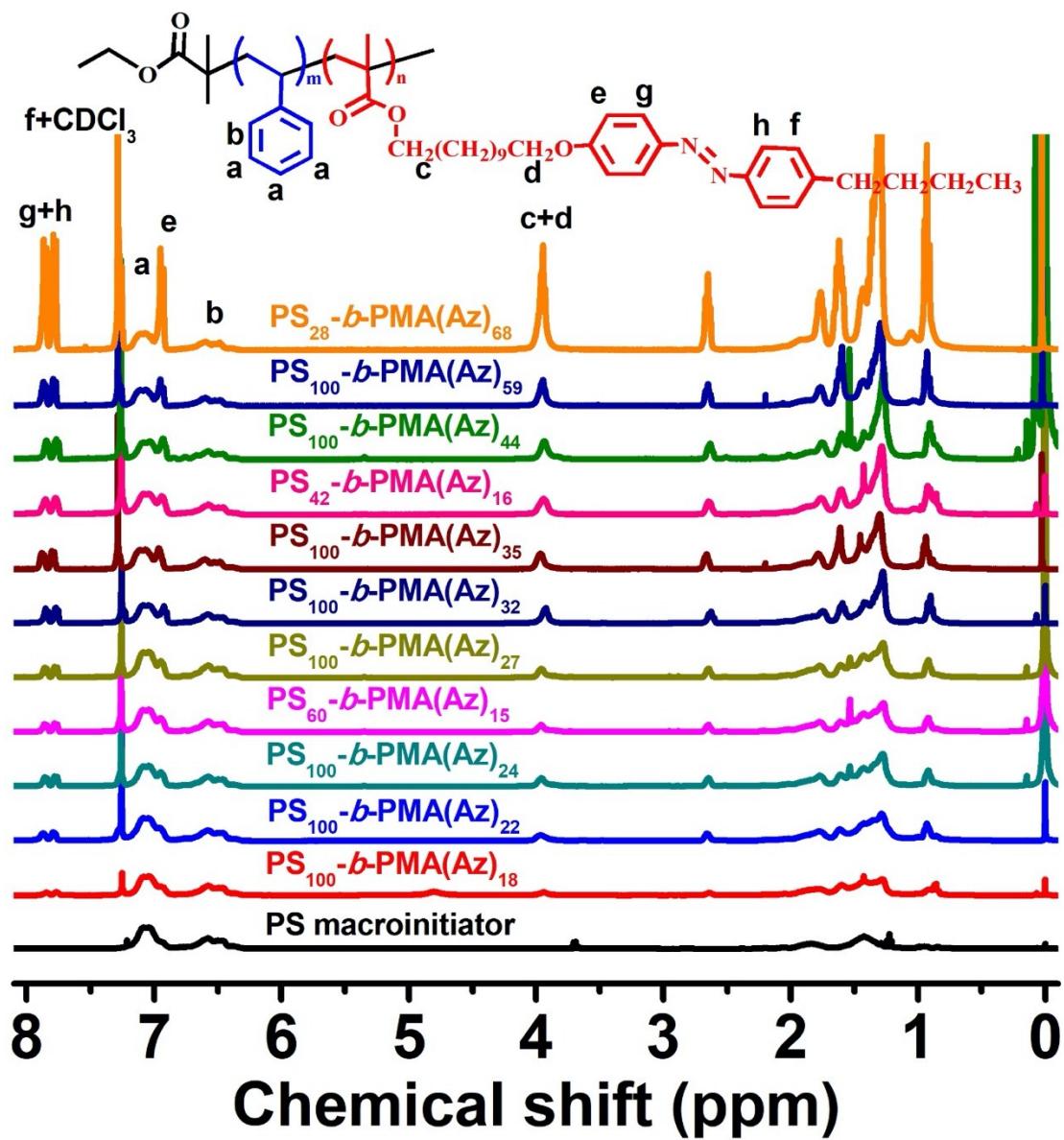


Fig. S1 ^1H NMR spectra of PS macroinitiators and PS-*b*-PMA(Az) BCPs.

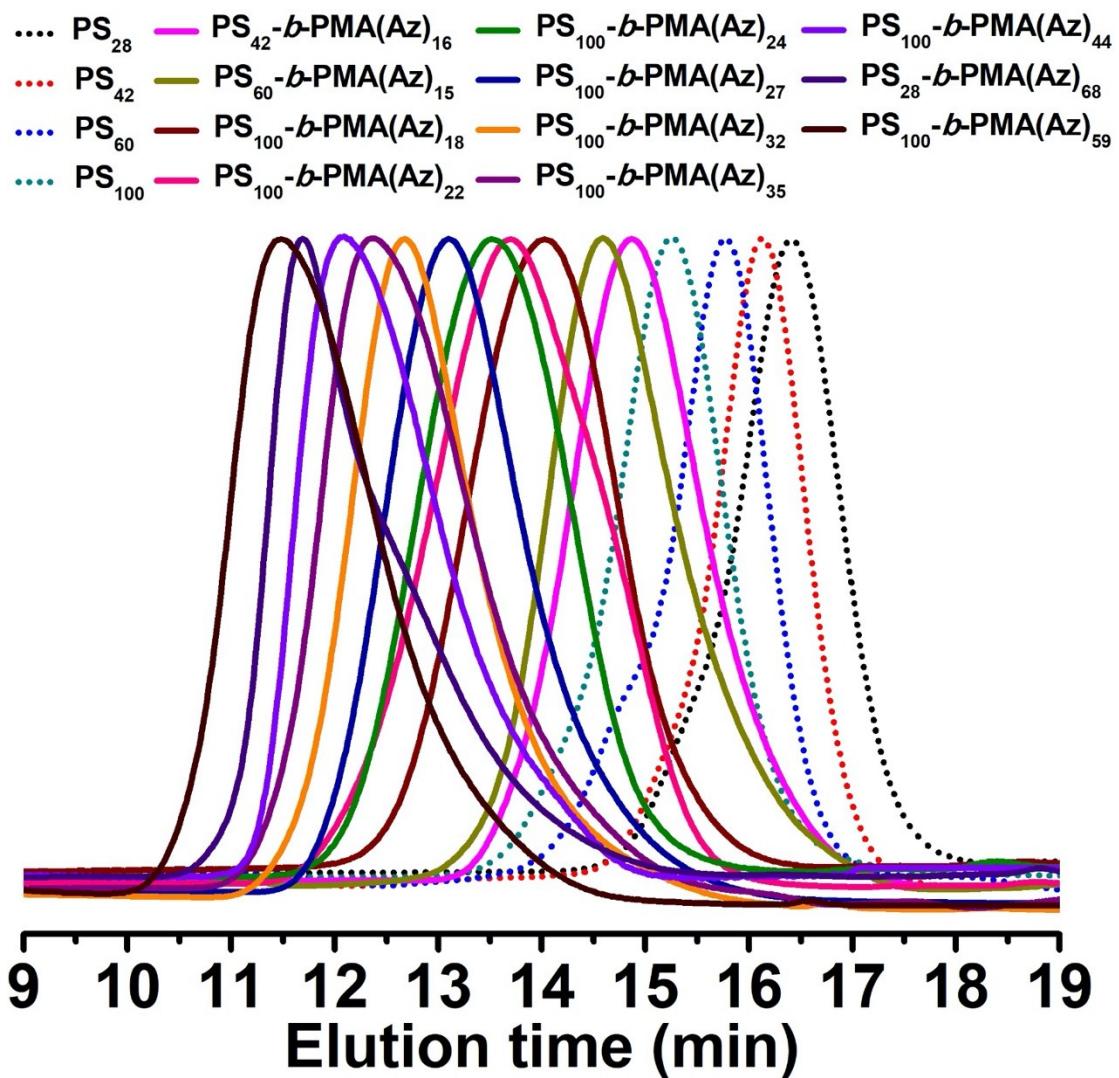


Fig. S2 GPC curves of the PS macroinitiators and PS-*b*-PMA(Az) BCPs with THF as eluent.

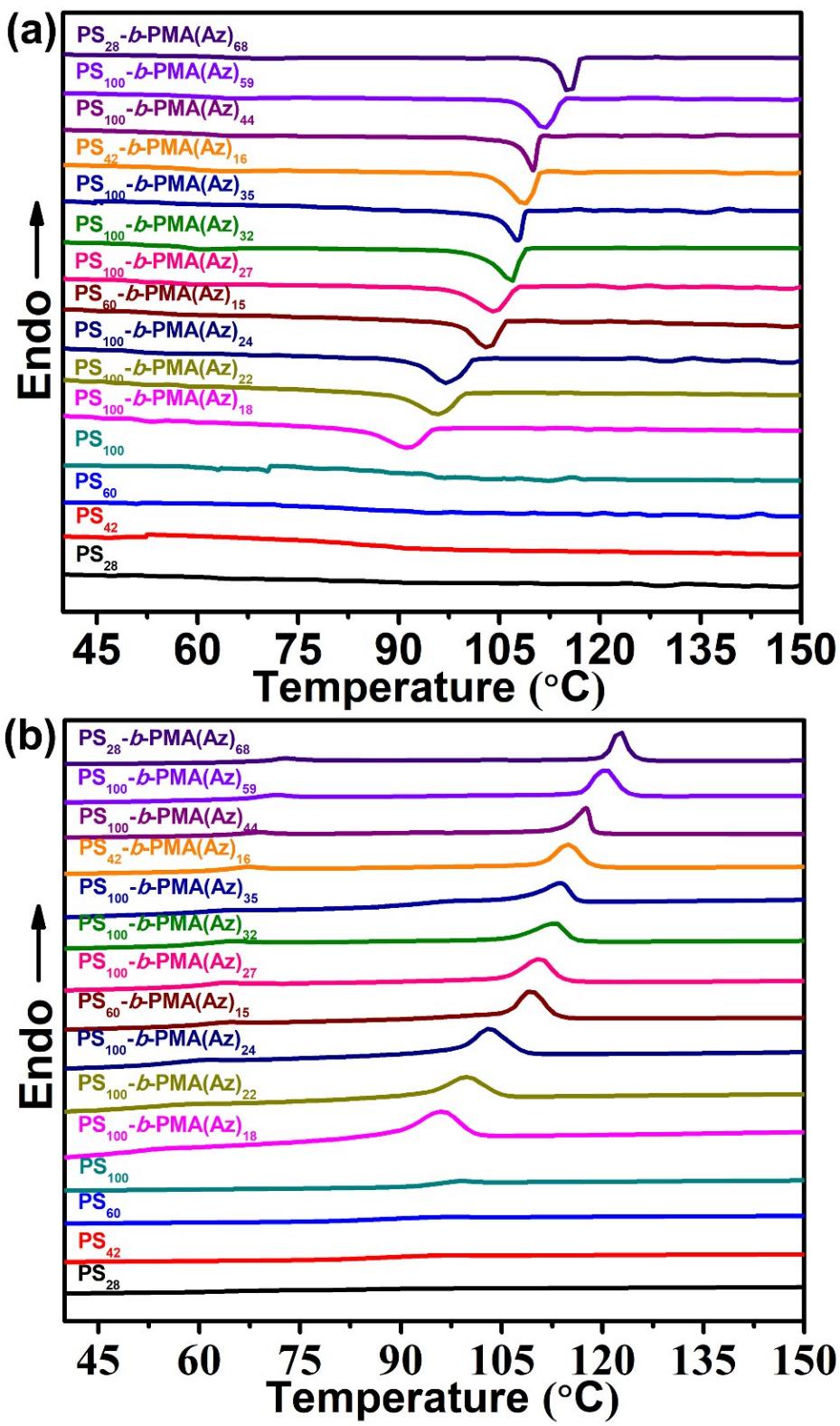


Fig. S3 DSC curves of polymers on the first cooling (a) and second heating (b) processes with a heating/cooling rate of $\pm 10\text{ }^{\circ}\text{C min}^{-1}$.

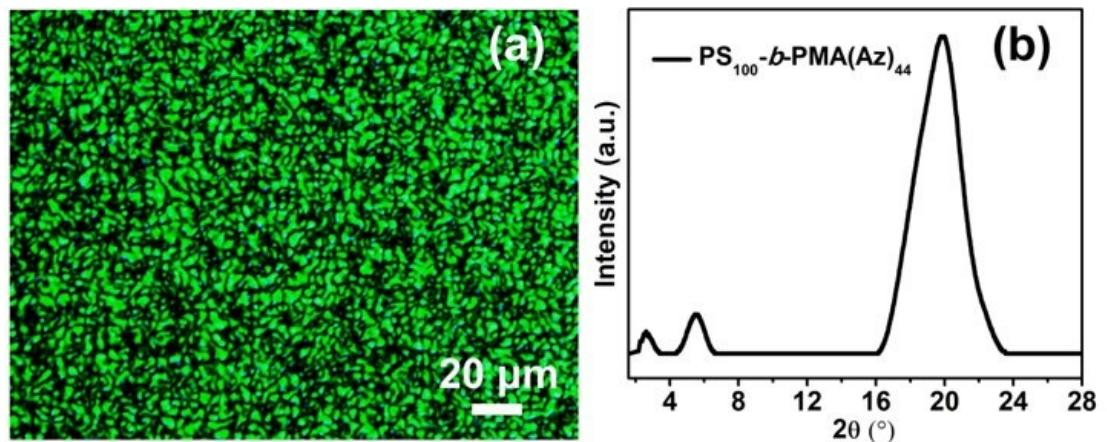


Fig. S4 POM image (a) and WAXD profile (b) of the $\text{PS}_{100}-b\text{-PMA(Az)}_{44}$ samples.

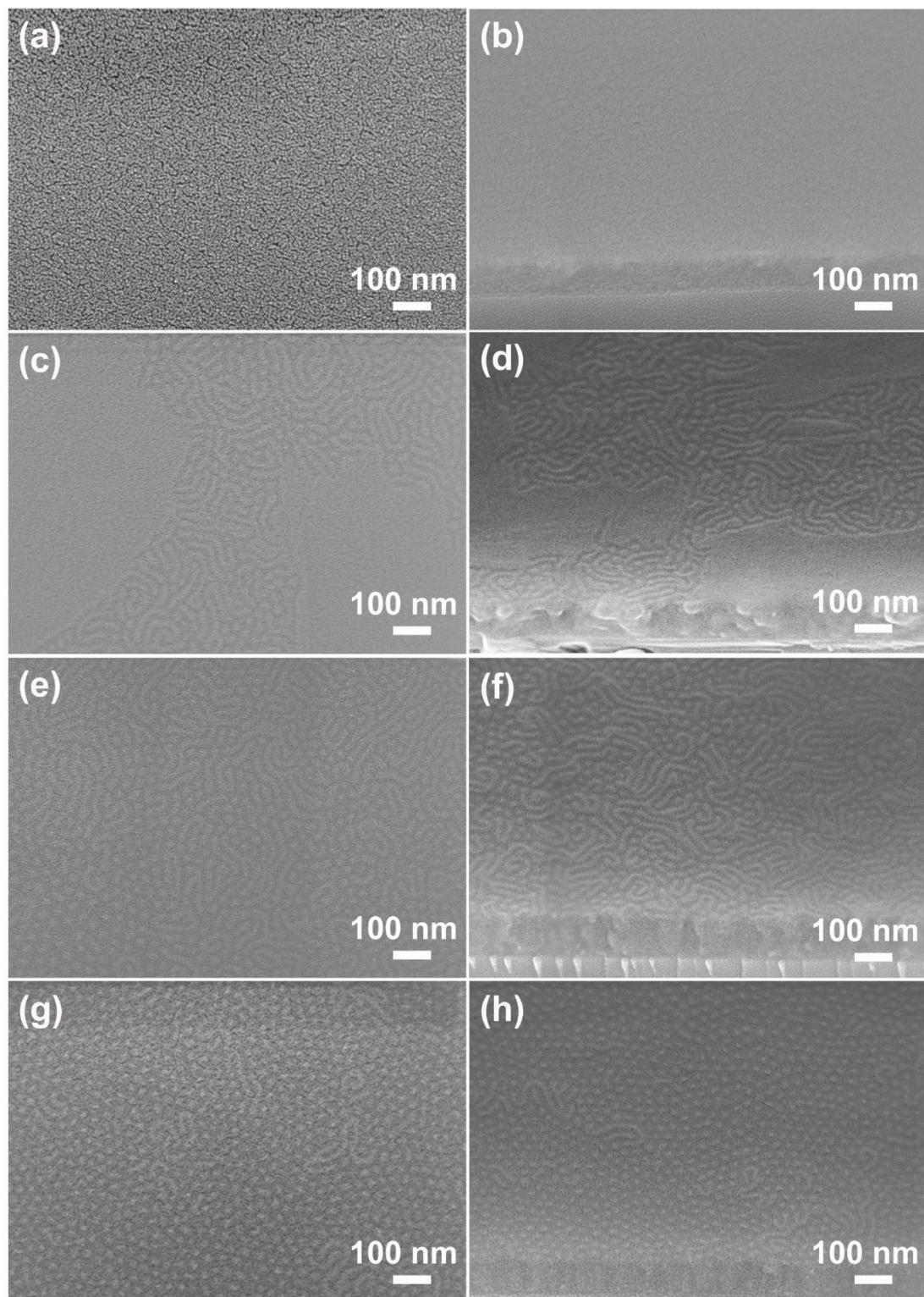


Fig. S5 SEM top (a, c, e, g) and cross-sectional (b, d, f, h) images of $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{44}$ thin films after thermal annealing at 140 °C for different times before RIE: (a, b) 0 min, (c, d) 1 min, (e, f) 3 min and (g, h) 5 min.

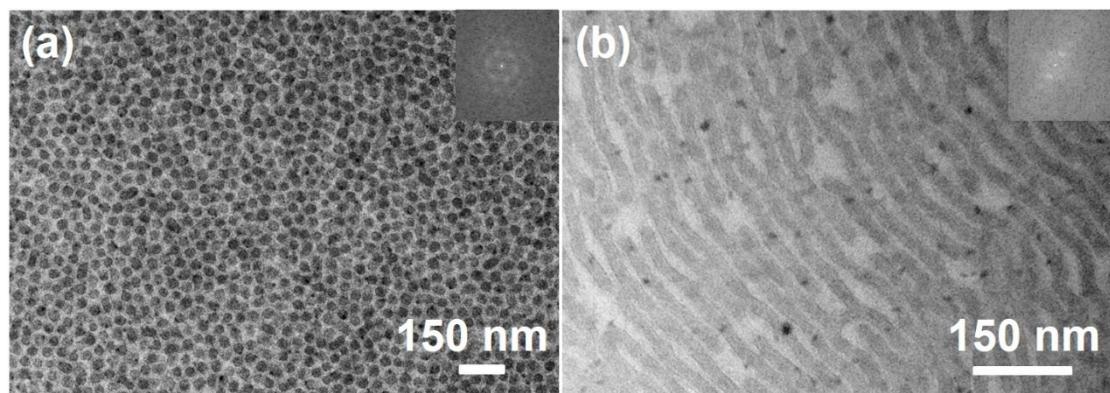


Fig. S6 TEM images (inset: FFT images) of cylindrical $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{44}$ (a) and lamellar $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{22}$ (b) thin films after thermal annealing at 140 °C for 5 min.

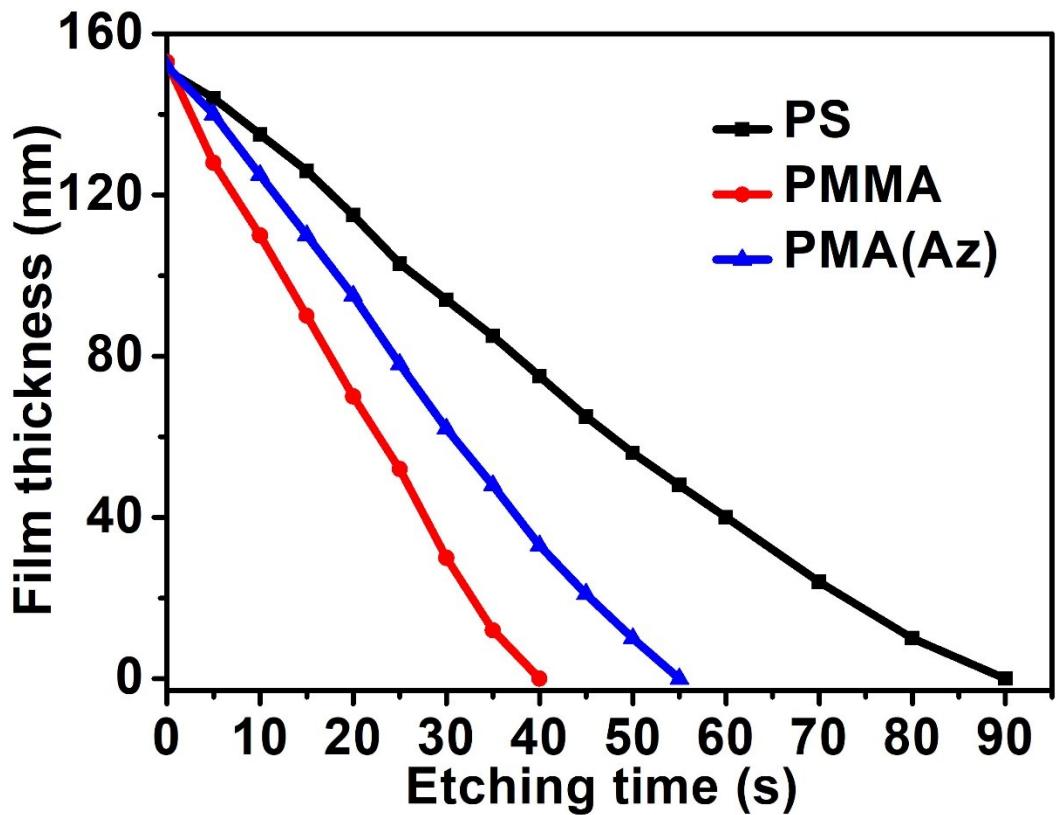


Fig. S7 The etching rate of PS, PMMA and PMA(Az) polymer films at the same RIE conditions: O₂/Ar (40/10) sccm/50 W/75 mTorr.

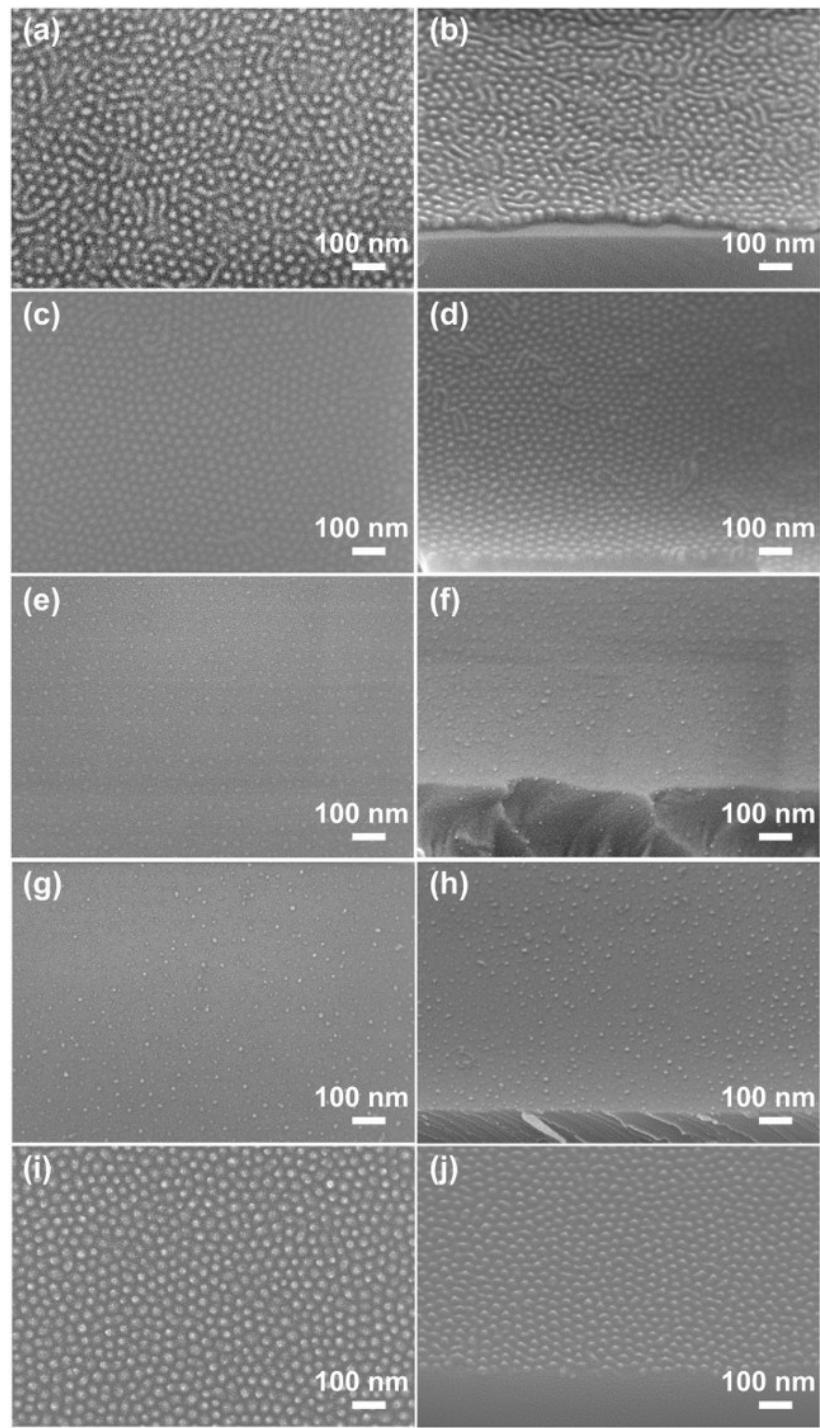


Fig. S8 SEM images of $\text{PS}_{100}-b\text{-PMA(Az)}_{44}$ self-assembled cylindrical films after different RIE conditions: (a, b) $\text{O}_2/50 \text{ sccm}/50 \text{ W}/75 \text{ mTorr}/30 \text{ s}$, (c, d) $\text{O}_2/\text{Ar} (15/3) \text{ sccm}/50 \text{ W}/75 \text{ mTorr}/30 \text{ s}$, (e, f) $\text{O}_2/\text{Ar} (40/10) \text{ sccm}/100 \text{ W}/75 \text{ mTorr}/30 \text{ s}$, (g, h) $\text{O}_2/\text{Ar} (40/10) \text{ sccm}/50 \text{ W}/75 \text{ mTorr}/60 \text{ s}$, (i, j) $\text{O}_2/\text{Ar} (40/10) \text{ sccm}/50 \text{ W}/75 \text{ mTorr}/30 \text{ s}$.

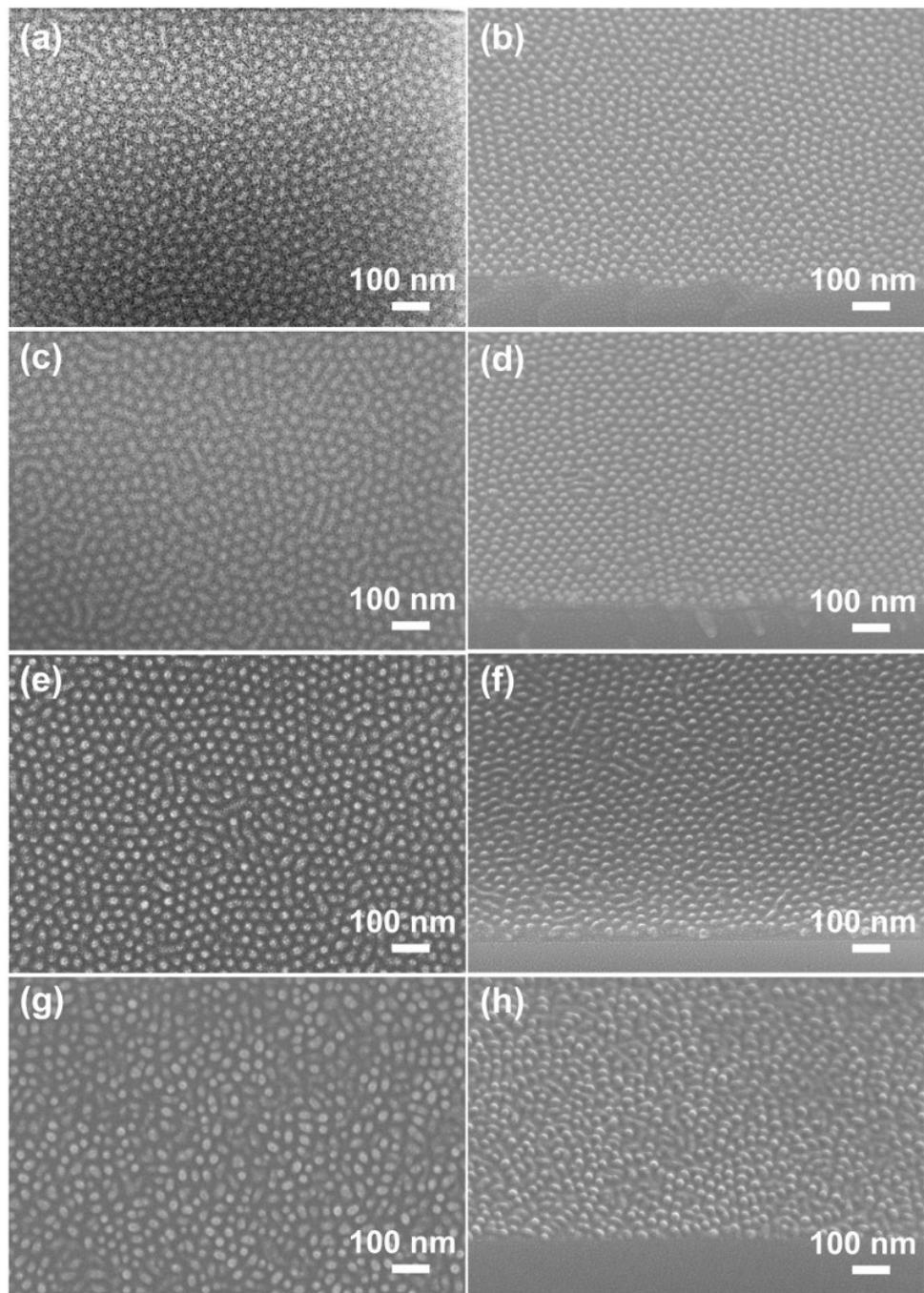


Fig. S9 SEM top (a, c, e, g) and cross-sectional (b, d, f, h) images of $\text{PS}_m\text{-}b\text{-PMA(Az)}_n$ self-assembled cylindrical films with different diameters after RIE: O_2/Ar (40/10) sccm/50 W/75 mTorr/30 s. (a, b) $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{59}$, (c, d) $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{35}$, (e, f) $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{32}$, (g, h) $\text{PS}_{100}\text{-}b\text{-PMA(Az)}_{27}$, respectively.

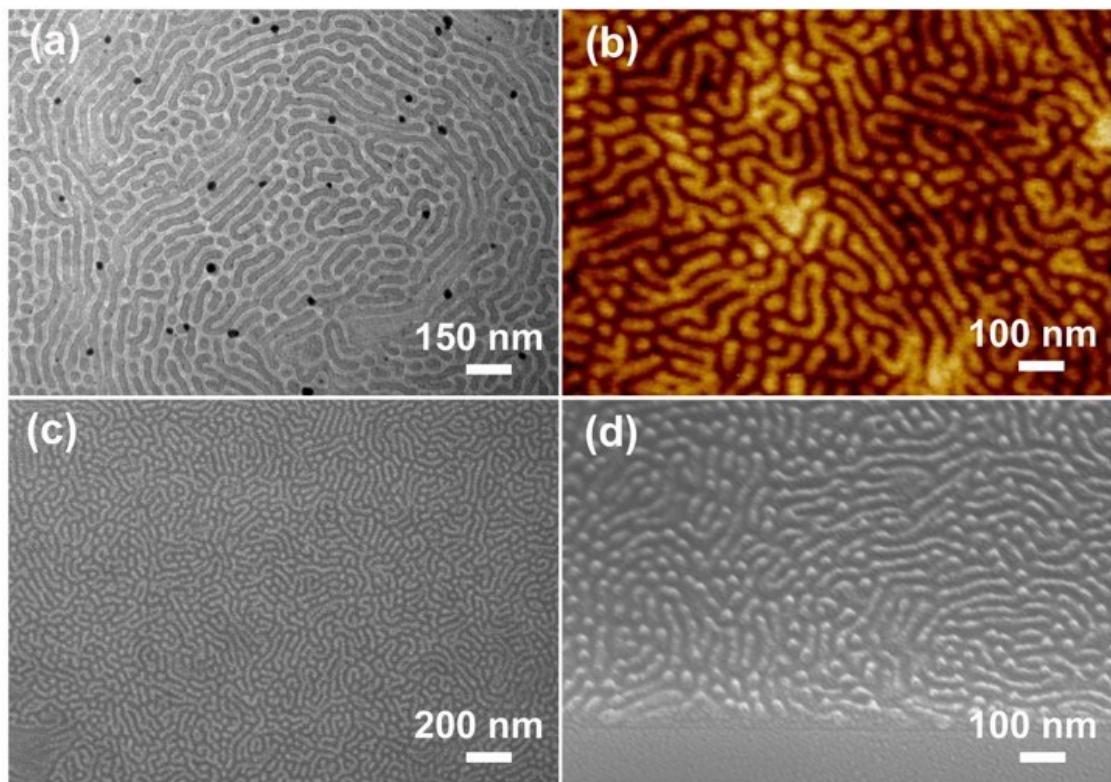


Fig. S10 TEM (a) and AFM (b) images of $\text{PS}_{100}-b\text{-PMA(Az)}_{24}$ self-assembled thin films. SEM top (c) and cross-sectional (d) images of above films after RIE: O_2/Ar (40/10) sccm/50 W/75 mTorr/30 s.

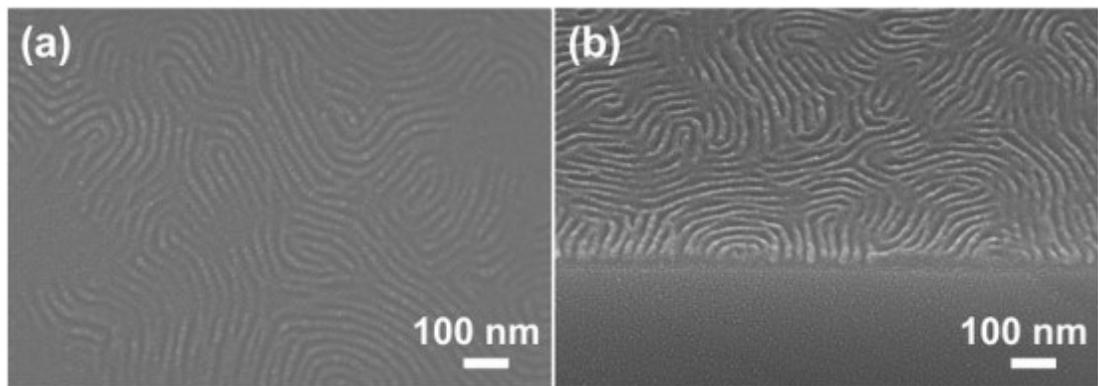


Fig. S11 SEM top (a) and cross-sectional (b) images of PS_{100} -*b*-PMA(Az)₁₈ self-assembled lamellar films after RIE: O₂/Ar (40/10) sccm/50 W/75 mTorr/30 s.

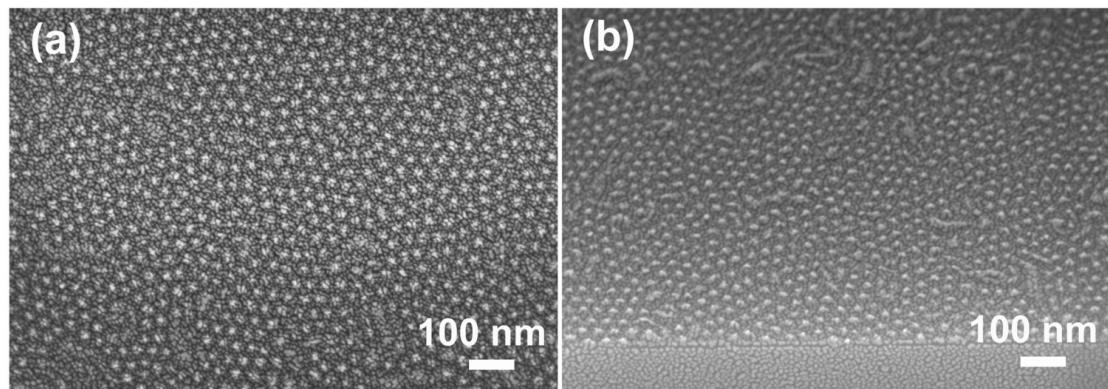


Fig. S12 SEM top (a) and cross-sectional (b) images of PS_{42} -*b*-PMA(Az)₁₆ films after RIE: O₂/Ar (40/10) sccm/50 W/75 mTorr/30 s.

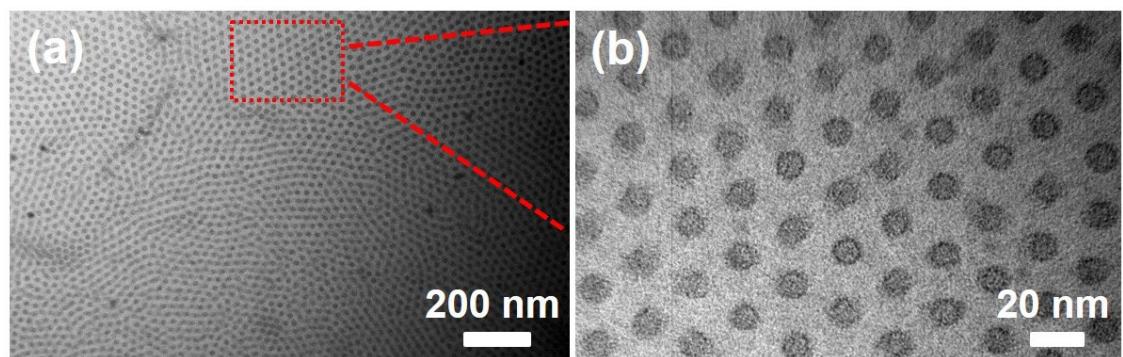


Fig. S13 (a) TEM image of cylindrical PS_{28} -*b*-PMA(Az)₆₈ thin film. (b) The magnification of the boxed area inserts in (a).

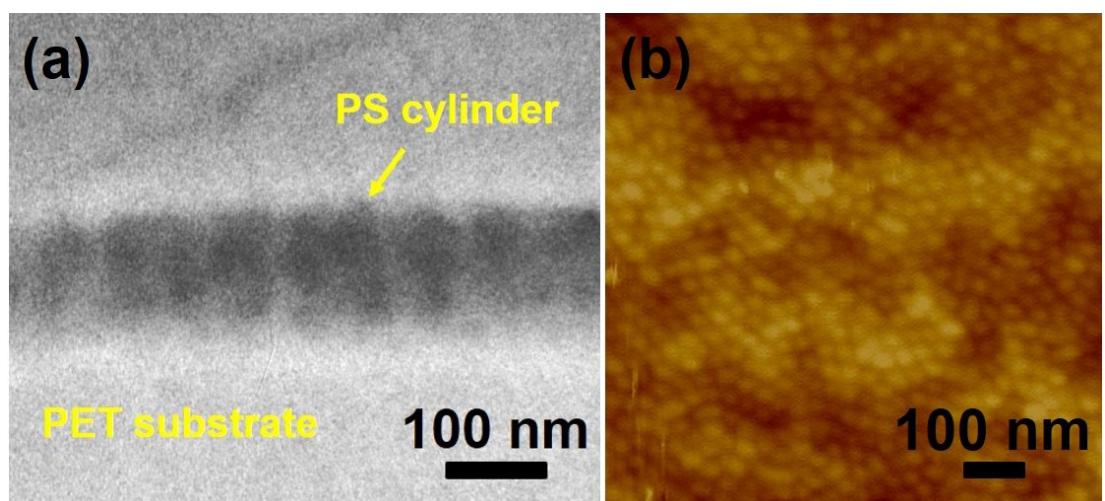


Fig. S14 Cross-sectional TEM (a) and top-view AFM height (b) images of the annealed PS_{100} -*b*-PMA(Az)₄₄ film on PET sheet.